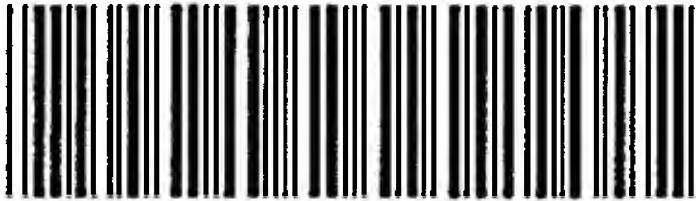


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,492	LIU ET AL.	
	Examiner	Art Unit	
	Victor J. Taylor	2863	

SEARCHED			
Class	Subclass	Date	Examiner
702	007	3/23/2005	VJT
324	339	3/29/2005	VJT
324	338	3/29/2005	VJT
324	343	3/29/2005	VJT
702	011	3/29/2005	VJT
707	007	3/29/2005	VJT
367	018	3/29/2005	VJT
703	005	3/29/2005	VJT
703	010	3/29/2005	VJT
702	014	3/29/2005	VJT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	007	3/31/2005	VJT
324	338	3/31/2005	VJT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consult Primary L. Arana for search in 324/338-339 and areas to search.	3/23/2005	VJT
EIC for publication on resistance modeling in seismic formations.	3/23/2005	VJT
East search for key terms and words in thin layer resistive modeling with key words.	3/29/2005	VJT
Plus search for key word and terms	3/31/2005	VJT
Consult primary Arana for addition search areas in 324/xxx.	3/31/2005	VJT